## Fast method for force computations in electronic structure calculations

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(Dated: April 14, 2024)

W e present new e cient (O (N  $\log N$ )) m ethods for computing three quantities crucial to electronic structure calculations: the ionic potential, the electron-ion contribution to the B om-O ppenheim er forces, and the electron-ion contribution to the stress tensor. The present m ethods are applicable to calculations in which the electronic charge density is represented on a uniform grid in real space. They are particularly well-suited for m etallic extended system s, where other O (N) m ethodologies are not readily applicable. Based on a fast algorithm for determ ining the atom ic structure factor, originally developed by E ssm ann et al. [1] for fast E wald energy and force computation, the present m ethods are tested on a representative m etallic system (bulk A l), and their ability to simultaneously achieve high accuracy and e ciency is demonstrated.

PACS num bers: 71.15.-m, 71.15.D x

A wealth of e cient methods have recently been developed [2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12] for calculating electronic properties of an extended physical system that require an am ount of com putation that scales linearly with the size of the system N. This size can be de ned to be the num ber of atom s or the num ber of valence electrons, or the volume of the system, all of which are linearly related for large condensed systems. In this article we present a quasi-linear-scaling (O (N log N )) method for com puting the ionic potential, the ionic forces, and the stress tensor in electronic structure calculations. A tom ic forces are necessary for the calculation of m any physical properties of a system, including the determ ination of the optim al structure and simulation at a nite tem perature. Som e linear-scaling m ethods achieve linear com putational scaling for the com putation of the energy but not for the forces on all of the ions[8]. O ther linear-scaling methods achieve e cient force calculations by working with a basis of localized functions [6, 9, 10], which are less e cient at representing delocalized electronic states found for example in metallic systems. The present m ethod applies to calculations perform ed in a periodic parallelepiped supercell, not necessarily orthogonal, in which the electronic charge density (r) is represented on a uniform grid.

As a result of the Hellm ann-Feynm an [13, 14] theorem, the force on the pth ion (within the Born-Oppenheimer approximation) is given by the sum of the partial derivatives of the ion-ion energy (the Ewald energy) and the electron-ion energy with respect to the atom ic coordinates:

$$F_{p} = F_{p}^{E \text{ wald}} + F_{p}^{e \text{ i}} = \frac{\Theta E^{E \text{ wald}}}{\Theta t_{p}} \quad \frac{\Theta E^{e \text{ i}}}{\Theta t_{p}} \quad (1)$$

where

$$E^{e i}$$
 (r)V<sup>ion</sup> (r)dr (2)

and the ionic potential is de ned as:

$$V^{\text{ion}}(\mathbf{r}) = V^{\text{psp}}(\mathbf{r} + \mathbf{t}_{p} + \mathbf{R})$$
(3)

where here the  $t_p$  are the atom ic positions within the unit cell; V psp (r) is the pseudopotential representing the ions; and the outer sum over R is over all lattice translation vectors  $R = n_1a_1 + n_2a_2 + n_3a_3$  for all integers n<sub>i</sub>, where the a<sub>i</sub> are the lattice vectors de ning the unit cell. For sim plicity of presentation, we will consider system s that involve only one type of pseudopotential, but the m ethods presented here generalize readily to system s with multiple pseudopotentials. Furtherm ore, non-local pseudopotentials can be split into a short-ranged nonlocal part and a long-ranged local part; only the longranged local part of V psp will be considered here. It should be noted that the present methods make only part of the electronic structure calculation e cient, and in the context of the Kohn-Sham method, the overall electronic structure calculation will still scale as N  $^3$  due to the need to orthogonalize N wavefunctions or to diaqonalize an N N matrix. Thus the present methods are particularly relevant to the orbital-free density functionalmethods[11, 12], which dealonly with local pseudopotentials and can achieve O (N) scaling for the entire calculation.

The Sm ooth Particle M esh Ewald M ethod [1] (SPM E) is an e cient scheme (O (N logN)) for computing the Ewald energy  $E^{E w a ld}$  and its derivatives with respect to the atom ic coordinates,  $@E^{E w a ld} = @t_p$ . Here we show how similar ideas can be used to yield e cient m ethods (also O (N logN)) for determining the ionic potential V <sup>ion</sup> (r), and the other component of the Born-Oppenheim er forces,  $@E^{e i} = @t_p$ .

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We begin presentation of our method by expressing V  $^{\rm ion}$  (r) in terms of the structure factor, S (r):

$$V^{ion}(\mathbf{r}) = \frac{1}{2} V^{psp}(\mathbf{r} \mathbf{r}^{0})S(\mathbf{r}^{0})d\mathbf{r}^{0}$$
 (4)

where

$$S(\mathbf{r}) = \begin{pmatrix} X & X^{at} \\ & & (\mathbf{r} & \mathbf{t}_{p} & R \end{pmatrix}$$
(5)  
$$R & p=1$$

and  $= ja_1$  (a  $a_3$ ) j is the unit cell volum e.

In reciprocal space, the expression for V  $^{\rm ion}$  becomes:  $$^{\rm Z}$$ 

$$\nabla_{Q}^{\text{ion}} = \frac{1}{-} \nabla^{\text{psp}} (Q) S_{Q}^{\text{on}}$$
(6)

where

$$\nabla^{\text{psp}}(Q) = V^{\text{psp}}(r)e^{iQ} dr$$
 (7)

and, using Eq. (5),

$$S_{Q} = \frac{1}{\sum_{\substack{\text{cell} \\ \text{sell}}}^{Z}} S(\mathbf{r}) e^{iQ} e^{\mathbf{r}} d\mathbf{r}$$
$$= \frac{\mathbf{k}^{at}}{e^{iQ} t_{p}}$$
(8)

Inversely, we have:

$$V^{\text{ion}}(\mathbf{r}) = \bigvee_{Q}^{X} \nabla_{Q}^{\text{ion}} e^{iQ \cdot \mathbf{r}}$$
(9)

where the Q -sum ranges over all integer multiples of the reciprocal lattice vectors  $b_i$  dened by  $a_i$   $b_i = 2_{ij}$ .

For the purposes of the present work, we assume that (r) is represented on a N<sub>1</sub> N<sub>2</sub> N<sub>3</sub> grid of points  $r_{l_1 l_2 l_3} = \frac{l_1}{N_1} a_1 + \frac{l_2}{N_2} a_2 + \frac{l_3}{N_3} a_3$ , with  $l_i = 0$ ; ...; N<sub>i</sub> 1. W e will denote quantities such as  $(r_{l_1 l_2 l_3})$  as  $(l_1; l_2; l_3)$ . The Fourier transform of (r) is approximated by:

$$(10) - (m_1b_1 + m_2b_2 + m_3b_3)' F[(l_1; l_2; l_3)]$$

where F is the discrete Fourier transform :

$$F [f (l_{1}; l_{2}; l_{3})] = \frac{1}{N} \frac{{}^{N_{X} 1} {}^{N_{X} 1} {}^{N_{X} 1} {}^{N_{X} 1} {}^{N_{X} 1} {}^{1} {}^{N_{X} 1} {}^{N_$$

where N N<sub>1</sub>N<sub>2</sub>N<sub>3</sub>. Its inverse, F<sup>1</sup>, is given by:

$$F^{1} [f(m_{1};m_{2};m_{3})] = f(m_{1};m_{2};m_{3})] = f(m_{1};m_{2};m_{3})$$

$$m_{1}=0 m_{2}=0 m_{3}=0$$

$$e^{2 i(\frac{l_{1}m_{1}}{N_{1}} + \frac{l_{2}m_{2}}{N_{2}} + \frac{l_{3}m_{3}}{N_{3}})(12)}$$

U sing Eq. (6), and transform ing back to the real space grid, we can determ ine V  $^{\rm ion}$  (r) via:

$$V^{\text{ion}} (l_1; l_2; l_3) = \frac{1}{-F^{-1}} F^{-1} F^{\text{im}} (m_1; m_2; m_3) S^{\text{im}} (m_1; m_2; m_3)$$
(13)

where  $P'(m_1; m_2; m_3)$  is the array given by:

$$\mathbb{P}(\mathfrak{m}_{1};\mathfrak{m}_{2};\mathfrak{m}_{3}) \quad \mathbb{V}^{\mathrm{psp}}(\mathfrak{m}_{1}^{0}b_{1} + \mathfrak{m}_{2}^{0}b_{2} + \mathfrak{m}_{3}^{0}b_{3}) \quad (14)$$

and  $m_i^0 = m_i$  for  $0 m_i N_i=2$  and  $m_i^0 = m_i N_i$ otherwise. The array  $S(m_1;m_2;m_3)$  is given by

 $S(m_1;m_2;m_3)$   $S(m_1b_1 + m_2b_2 + m_3b_3)$  (15)

Calculation of the structure factor via Eq. (8) will scale with the square of the system size, because it needs to be computed at every reciprocal space grid point  $(m_1;m_2;m_3)$ , and at each of these points a sum must be performed over each atom in the system. However, E ssm ann et al., as part of their e cient Sm ooth Particle M esh Ewald method[1], provide an elegant method for computing the structure factor e ciently (albeit approximately), requiring an amount of computation that scales as only N logN. By incorporating this algorithm to compute the structure factor, the present methods for computing both the ionic potential V ion (r) and the electron-ion contribution to the forces  $F_p^{e}$  i achieve the sam e O (N logN) quasi-linear scaling.

Here we sum marize the method of Essmann et al. for e ciently computing the structure factor, but refer the reader to the original reference [1] for full details. The crux of the algorithm lies in the approximation of the exponential in Eq. (8) with (com plex) cardinal B-splines. The nth order cardinal B-spline function,  $M_n(x)$ , is dened as follows:  $M_2(x) = 1$  jx 1j for 0 x < 2, and  $M_2(x) = 0$  otherwise; and the higher-order cardinal B-splines are de ned recursively:

$$M_{n}(x) = \frac{x}{n-1}M_{n-1}(x) + \frac{n-x}{n-1}M_{n-1}(x-1)$$
 (16)

We de ne the grid coordinates of the pth atom as  $u_{ip}$ N<sub>i</sub>t<sub>p</sub> b, or equivalently  $t_p = \frac{u_{1p}}{N_1}a_1 + \frac{u_{2p}}{N_2}a_2 + \frac{u_{3p}}{N_3}a_3$ . The structure factor, expressed in terms of the grid co-ordinates, is:

$$S(m_{1};m_{2};m_{3}) = \sum_{p=1}^{X^{at}} \exp 2 i \frac{m_{1}}{N_{1}} u_{1p}$$
$$\exp 2 i \frac{m_{2}}{N_{2}} u_{2p} \exp 2 i \frac{m_{3}}{N_{3}} u_{3p} \qquad (17)$$

The exponentials can be approximated by nth order cardinalB-splines, where n is even, as:

exp 2 
$$i \frac{m_{j}}{N_{j}} u_{jp}$$
 '  $b_{j} (m_{j}) \overset{X^{i}}{\underset{k=1}{}} M_{n} (u_{jp} k)$   
exp 2  $i \frac{m_{j}}{N_{j}} k$  (18)

where b<sub>j</sub> (m <sub>j</sub>) is:

$$b_{j}(m_{j}) = \frac{\exp(2 i(n - 1)m_{j} = N_{j})}{\prod_{k=0}^{m_{2}} M_{n}(k + 1) \exp(2 i \frac{m_{j}}{N_{j}}k)}$$
(19)

W hen this B-spline approximation of the exponential is used in Eq. (17), it becomes a discrete Fourier transform :

$$S(m_{1};m_{2};m_{3})' B(m_{1};m_{2};m_{3})$$

$$X^{at} X^{b}$$

$$M_{n}(u_{1p} k_{1})M_{n}(u_{2p} k_{2})$$

$$p=1k_{1};k_{2};k_{3}=1$$

$$M_{n}(u_{3p} k_{3})e^{2} i \frac{m_{1}k_{1}}{N_{1}} + \frac{m_{2}k_{2}}{N_{2}} + \frac{m_{3}k_{3}}{N_{3}}$$

$$= N B(m_{1};m_{2};m_{3})F[Q(L_{1};L_{2};L_{3})]$$
(20)

where

$$B^{*}(m_{1};m_{2};m_{3}) \qquad b_{1}(m_{1})b_{2}(m_{2})b_{3}(m_{3}) \qquad (21)$$

and:

$$Q (l_{1}; l_{2}; l_{3}) = \begin{array}{c} X^{at} & X^{b} \\ & M_{n} (u_{1p} \quad l_{1} \quad c_{1}N_{1}) \\ & P^{= 1 c_{1}; c_{2}; c_{3} = 1} \\ M_{n} (u_{2p} \quad l_{2} \quad c_{2}N_{2})M_{n} (u_{3p} \quad l_{3} \quad c_{3}N_{3}) (22) \end{array}$$

The array Q ( $l_1$ ;  $l_2$ ;  $l_3$ ) can be computed quickly (O (N<sup>at</sup>)), because it is only non-zero for sub-cubes of dimension n n located near each atom. It is because F [Q] can be computed with the fast Fourier transform (FFT) (which is performed in O (N log N) operations) that the structure factor itself can be computed with O (N log N) operations.

It is now easily seen how the structure factor algorithm provided by the SPM E m ethod can be used to yield an e cient m ethod for computing V <sup>ion</sup>  $(l_1; l_2; l_3)$ . By substituting Eq. (20) into Eq. (13), we obtain:

$$V^{\text{ion}}(l_{1}; l_{2}; l_{3}) = \frac{N}{-}F^{-1} P^{\text{m}}(m_{1}; m_{2}; m_{3})B^{\text{m}}(m_{1}; m_{2}; m_{3})$$

$$F [Q(l_{1}; l_{2}; l_{3})] (23)$$

In practice, Eq. (23) could be used to e ciently compute V<sup>ion</sup>  $(l_1; l_2; l_3)$  with the following algorithm. First Q  $(l_1; l_2; l_3)$  is computed via Eq. (22). Then F [2] is obtained via the FFT.F [2] is then multiplied by B and P, de ned by Eqs. (21) and (14). Then the inverse FFT of this product is computed and multiplied by N = , yielding the array V<sup>ion</sup>  $(l_1; l_2; l_3)$ .

The calculation of the electron-ion contribution to the ionic force,  $@E^{e^i} = @t_p$  can also be made e cient, and again this comes from expressing  $@E^{e^i} = @t_p$  in terms of the structure factor. In the discrete variable representation, the expression for the pseudopotential energy, Eq. (2), becomes:

$$E^{e_{1}} \cdot \frac{X}{N} (l_{1}; l_{2}; l_{3}) V^{ion} (l_{1}; l_{2}; l_{3})$$
(24)

which can be viewed as a dot product of and V <sup>ion</sup>; we can also evaluate this dot product in reciprocal space, and taking into account that is an array of real numbers, the expression becomes:

$$E^{e_{1}} = F[(l_{1}; l_{2}; l_{3})] F V^{ion}(l_{1}; l_{2}; l_{3}) (25)$$

then, using Eq. (23) for  $V^{ion}$ , this becomes:

$$E^{e_{1}} \cdot N \qquad F[(l_{1}; l_{2}; l_{3})] P(m_{1}; m_{2}; m_{3})$$

$$m_{1}; m_{2}; m_{3}$$

$$B(m_{1}; m_{2}; m_{3}) F[Q(l_{1}; l_{2}; l_{3})] \qquad (26)$$

Following this substitution, we now express the dot product in real space again:

$$E^{ei}, X \qquad h \\ E^{ei}, Q(l_{1}; l_{2}; l_{3})F^{1}F[(l_{1}; l_{2}; l_{3})] \\ \downarrow_{l_{1}; l_{2}; l_{3}} \qquad i \\ P^{e}(m_{1}; m_{2}; m_{3}) B^{e}(m_{1}; m_{2}; m_{3}) \qquad (27)$$

Because the only factor that depends on the atom ic positions is Q, we can readily di erentiate with respect to the atom ic positions:

$$\frac{\mathcal{Q}E^{e\,i}}{\mathcal{Q}t_{p}} = \frac{X}{\frac{\mathcal{Q}Q}{\mathcal{Q}t_{p}}} F^{1}F[(l_{1};l_{2};l_{3})]$$

$$\tilde{F}(m_{1};m_{2};m_{3})\tilde{F}(m_{1};m_{2};m_{3})$$
<sup>i</sup>
<sup>(28)</sup>

where = 1;2;3 is the vector component of the force. Eqs. (23) and (28) (and the expression for the stress tensor, Eq. (A3)) constitute the central results of this article.

The partial derivatives  $@Q = @t_p$  can be evaluated readily with the de nition of Q, Eq. (22), and with the aid of the following B-spline identity:

$$\frac{d}{dx}M_{n}(x) = M_{n-1}(x) \quad M_{n-1}(x-1)$$
(29)

C om puting the partial derivatives of Eq. (28) for all of the atom s in the system requires an am ount of com – putation that scales as N logN. As with Q, the partial derivative array  $@Q = @t_p (l_1; l_2; l_3)$  is only non-zero in sub-cubes near the atom ic positions, so com puting it requires O (N) com putation. The fast Fourier transform s scale as N logN.

The application of Eq. (28) for rapid computation of the electron-ion forces  $F^{e\ i}$  can proceed algorithm ically as follows. The Fourier transform of  $(l_1;l_2;l_3)$  is computed; then F [] is multiplied by P' and B'. Then the inverse Fourier transform of this product is found. Then by utilizing Eq. (29), the derivatives  $Q = \text{@t}_p \quad (l_1;l_2;l_3)$  are computed during the sum m ing over the  $l_i$ 's, yielding  $Q \equiv ^{e\ i} = \text{@t}_p$ .

Similar ideas can yield an e cient expression for the computation of the stress tensor. The details of the e - cient stress tensor m ethod are covered in the appendix.

A lthough these m ethods have been presented assum ing that only one type of pseudopotential (and hence only one type of ion) is present in the system, multiple types are readily treated. Since the ionic potential is a linear function of the pseudopotentials, then with multiple types of pseudopotentials the total ionic potential is a sum of ionic potentials of the di erent types,

$$V_{\text{tot}}^{\text{ion}}(\mathbf{l}_{1};\mathbf{l}_{2};\mathbf{l}_{3}) = V^{\text{ion}}(\mathbf{l}_{1};\mathbf{l}_{2};\mathbf{l}_{3})$$
(30)

where indexes the pseudopotential type. The individual V <sup>ion</sup> are each computed with Eq. (23) using the Q -array associated with this set of ions, and the  $\tilde{P}$ -array associated with this pseudopotential type. Likewise to compute the ionic forces, Eq. (28) is used to compute the forces on all ions of a given pseudopotential type, using the Q -array associated with this set of ions, and the  $\tilde{P}$ -array associated with this pseudopotential type.

Several tests have been perform ed to exam ine the accuracy of these m ethods. The accuracy of the approxim ate structure factor, Eq. (20), increases when the number of grid points N increases, and when the B-spline order n is increased. However, in an electronic structure calculation, one is not simply free to choose the number of grid points for computing S. It is clear from Eqs. (23) and (28) that S and the electronic charge density must exist on the same grid, and typically energy convergence considerations dictate a m inim um grid density on which

is represented. So it must be established that for a given grid density, the error incurred by using the approximate S when generating V ion and calculating the forces (i.e. the present methods, Eqs. (23) and (28)) is not much more than the error that would be present using the same nite number of grid points and the exact structure factor S when generating V ion and calculating the forces. In other words, it must be shown that the error in the total energy and forces that com es from using an approximate S is smaller than the error due to using a grid of nite density. Furtherm ore, in order to establish that these methods are indeed (quasi) linear scaling, it must be demonstrated that for a xed grid density N = and xed B-spline ordern, the error per atom due to the approximate S does not increase when the system size is increased.

All tests here have been done on systems of aluminum atoms simulated with orbital-free density functional theory [11, 12]. The present methods for generating V<sup>ion</sup> (r<sub>i</sub>) (i.e. the method of Eq. (23)) and F<sup>e i</sup> (Eq. (28)) were tested as follows: rst, in order to test the error due to the approximate S<sup>c</sup> compared to the error from the rest of the calculation, 32 Al atoms were placed in a cubic box 8:08A on a side, and displaced random ly by about 0:5A from their fcc crystalline positions. Then V<sup>ion</sup> was generated using the exact S<sup>c</sup> (Eq. (8)), and the present method (Eq. (23)) with B-spline orders n = 6;8;10;12, and separate electronic relaxations were done in each of these V<sup>ion</sup>'s, yielding corresponding total energies. A fter electronic relaxation, electron-ion forces

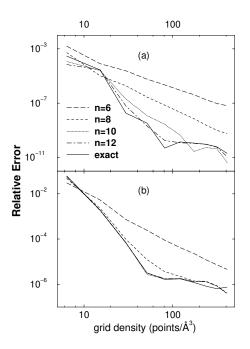


FIG.1: (a) Relative error in the energy compared to in nite grid density limit, Eq. (31). (b) Relative error in  $F^{e i}$ compared to the in nite grid limit, Eq. (32).

 $F^{e}$  i were calculated using derivatives of the exact *S*, and with the present method (Eq. (28)). This was done for successively higher grid densities. The results are shown in Fig. 1. The relative error between the energy and the converged energy, as measured by:

$$\frac{\underline{j} \underline{E} \underline{E}^{1} \underline{j}}{\underline{F}^{1} \underline{j}}$$
(31)

(where E<sup>1</sup> is the energy in the limit of in nite grid density) is plotted as a function of grid density for di erent choices of V ion : V ion generated with the exact m ethod and the present method.  $E^{1}$  is taken to be the total energy evaluated with a grid density of 800 points/A<sup>3</sup>, a considerably higher density than plotted in Fig. 1; thus the deviation from this grid's energy from the true  $E^{1}$ is of a smaller order of magnitude than the energy deviations found at the grid densities explored in Fig. 1, making it a suitable energy to use as  $E^{1}$  . It is clear that with a B-spline order of n = 10 the error due to the use of the approxim ate V ion is negligible com pared to the error due to the nite grid density. A loo plotted is the relative error in the calculated electron-ion forces F  $^{\rm e}$  i . The method used for calculating the force corresponded to the method used to calculate V<sup>ion</sup>; e.g. the data for the forces calculated with the present method and a 6th order B-spline were done with charge densities relaxed in a V<sup>ion</sup> generated with the present m ethod with a 6th order B-spline. Thus errors in the forces that were calculated with the present method have some error contribution from using the present method for generating V<sup>ion</sup>. The relative force error was measured as the fractional root-

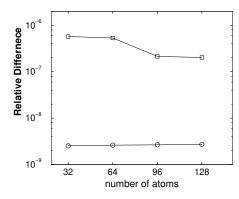


FIG. 2: The relative di erence between the total energy (circles) and forces (squares) calculated with the present m ethods and with the exact structure factor m ethods, as a function of system size (see Eqs. (31) and (32)).

m ean-square deviation of each force component on each atom :

$$\frac{P_{N_{at}}P_{I=1}}{\frac{I_{at}}{P_{at}}P_{I=1}} \frac{(F_{i} F_{i}^{1})^{2}}{(F_{i}^{1})^{2}} = (32)$$

where the  $F_1^1$  's are the forces in the limit of in nite grid density, in the same sense as expained above for  $E^1$ . In this case, already at a B-spline order of n = 8 the forces are alm ost as accurate as those calculated with the exact m ethod, and for n = 10;12 the forces are indistinguishable.

Second, in order to verify the scaling of these methods for di erent system sizes, four di erent system swere considered. For system s of 32, 64, 96, and 128 A latom s, displaced from crystalline positions as before, V ion was generated with the exact S, and with an approximate S generated with 8th-order B-splines. The grid density in each case was 237 points=A. A fter electronic relaxation, forces were calculated using the exact S or with the present m ethod, again corresponding to the m ethod used to generate V  $^{\rm ion}$  . The relative error between these energies and forces as a function of system size is plotted in Fig. 2. The relative errors are measured as before, with expressions like Eqs. (31) and (32), but instead of comparing to the energy and forces of the in nite grid density limit, the energy and forces are compared to those calculated using the same grid density and the exact structure factor of Eq. (8). The relative error in the energy is seen to be constant as a function of system size, and the relative error in the forces is actually seen to decrease slightly with increasing system size. Thus su cient accuracy can be achieved with the present m ethods for calculating V<sup>ion</sup> and the F<sup>ei</sup> using a xed B-spline order and grid density, con ming that these methods will scale quasi-linearly with system size.

F inally, the time required to generate V  $^{ion}$  with the exact and present m ethods, and to evaluate the electron-ion forces with the exact and the present m ethods is plotted

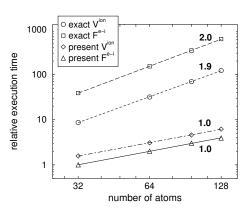


FIG.3: The computation time required to generate V  $^{\rm ion}$  and evaluate the F  $^{\rm e~i}$  's as a function of num ber of atom s, for the traditional and present m ethods. The num bers on each curve represent the exponent of a power law t.

in Fig. 3. One unit of time in the gure corresponded to 1:38 seconds of execution time on a 450 M H z Pentium III processor. The present m ethods are far superior even for m odest num bers of atom s. It is also noted that the present m ethods are readily parallelized.

In conclusion, we present accurate and e cient methods for computing the ionic potential and the Born-Oppenheimer forces on atoms by utilizing an approximate form of the structure factor. It has been demonstrated that the errors due to the present m ethods do not increase with increasing system size. As is typically the case with approximate numerical methods, there is a trade-o between accuracy and e ciency with the present methods. Accuracy can be system atically im proved by increasing the grid density or by increasing the B-spline order n, both at the expense of m ore com puting time. However, it was demonstrated that the errors introduced by using the present m ethods at a B-spline order of n = 10 are sm all com pared to errors in other parts of the electronic structure calculation that arise due to the use of a nite grid density. Thus a B-spline order of 10 is recommended as the optimal compromise for simple m etals like A l, which was used here as a test case.

## APPENDIX A : THE ELECTRON -ION CONTRIBUTION TO THE STRESS TENSOR

The present m ethods are readily applied to the com putation of the electron-ion contribution to the stress tensor can be calculated with them ethods of N ielsen and M artin [15]. One constructs an ionic potential skew ed by a strain tensor , and a density similarly skew ed and scaled to preserve norm alization:

$$V^{\text{ion}}(\mathbf{r}) \qquad V^{\text{ion}}((\mathbb{I} + )^{1}\mathbf{r}); \qquad (A1)$$

$$(\mathbf{r}) \qquad [\det(\mathbb{I} + )]^{1}((\mathbb{I} + )^{1}\mathbf{r})$$

The electron-ion contribution to the stress density tensor is then given by:

$$e_{i} = \frac{e_{i}}{e} = \frac{e_{i}}{e} = \frac{e_{i}}{e}$$
(r)V<sup>ion</sup>(r)dr(A2)

Under the strain transformation, the structure factor is unchanged, and the Fourier components of the density, F [  $(l_1; l_2; l_3)$ ], are simply scaled by [det (l + )]<sup>1</sup>. The reciprocal lattice vectors, to rst order in , become  $b_i$  ! (l ) $b_i$ , and hence  $(b_i = 0 = b_i \cdot D)$  ifferentiating Eq. (26) with respect to , one obtains an e cient method for the electron-ion stress density tensor:

$${}^{e i} = \frac{E^{e i}}{m_{1};m_{2};m_{3}} \frac{Q Q}{Q p} P^{0}(m_{1};m_{2};m_{3})F[(l_{1};l_{2};l_{3})] B'(m_{1};m_{2};m_{3})F[Q(l_{1};l_{2};l_{3})]$$
(A3)

where Q  $m_1^0b_1 + m_2^0b_2 + m_3^0b_3$ , and  $F^0(m_1;m_2;m_3)$   $d\nabla^{psp}(Q) = dQj$ . This method has been subjected to simple tests comparing the derivative of the energy with respect to the crystal lattice constant to the components of the stress tensor.

These tests indicate an accuracy similar to the present force method. It must be noted, however, that unlike the ionic forces, the cell stress has contributions from all terms in the energy, and  $e^{i}$  is merely one of them.

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